12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20170327000
Qualification of MIHO8 as an additional Wafer Fab Site option for select devices
Change Notification / Sample Request

Date: March 29, 2017
To: Newark/Farnell PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN_ww_admin_team@list.ti.com).

PCN Team
SC Business Services

20170327000
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
LM43600PWPT	null
LM43601PWPT	null
LM43602PWPT	null
LM43603PWPT	null
LM46000PWPT	null
LM46001PWPT	null
LM46002PWPT	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20170327000	**PCN Date:**	Mar 29, 2017
Title:	Qualification of MIHO8 as an additional Wafer Fab Site option for select devices in LBC8 Technology		
Customer Contact:	PCN Manager	**Dept:**	Quality Services
Proposed 1st Ship Date:	Jun 29, 2017	**Estimated Sample Availability:**	Date provided at sample request.

Change Type:

☐	Assembly Site	☐	Assembly Process	☐	Assembly Materials
☐	Design	☐	Electrical Specification	☐	Mechanical Specification
☐	Test Site	☐	Packing/Shipping/Labeling	☐	Test Process
☐	Wafer Bump Site	☐	Wafer Bump Material	☐	Wafer Bump Process
☒	Wafer Fab Site	☐	Wafer Fab Materials	☐	Wafer Fab Process
		☐	Part number change		

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its MIHO8 fabrication facility as an additional Wafer Fab source for the selected devices listed in "Product Affected" section.

Current Sites			Additional Sites		
Current Fab Site	**Process**	**Wafer Diameter**	**Additional Fab Site**	**Process**	**Wafer Diameter**
DP1DM5	LBC8	200mm	MIHO8	LBC8	200mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	DM5	USA	Dallas

New Fab Site

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
MIHO8	MH8	JPN	Ibaraki

Sample product shipping label (not actual product label)

Product Affected:			
LM43600PWP	LM43602PWP	LM43603PWPT	LM46001PWPR
LM43600PWPR	LM43602PWPR	LM46000PWP	LM46001PWPT
LM43600PWPT	LM43602PWPT	LM46000PWPR	LM46002PWP
LM43601PWP	LM43603PWP	LM46000PWPT	LM46002PWPR
LM43601PWPR	LM43603PWPR	LM46001PWP	LM46002PWPT
LM43601PWPT			

Qualification Report
LM46002PWP
Approve Date 24-Feb-2017

Product Attributes

Attributes	Qual Device: LM46002PWPR
Assembly Site	TI – Taiwan
Package Family	HTSSOP
Flammability Rating	UL 94 V-0
Wafer Fab Supplier	TI – Japan
Wafer Fab Process	Power BiCMOS LBC8

- Qual Device LM46002PWPR is qualified at LEVEL3-260C

Qualification Results
Data Displayed as: Number of lots / Total sample size / Total failed

	Type	Test Name / Condition	Duration	Qual Device: LM46002PWP
	PC	Preconditioning Level 3	260C	3/693/0
	HTOL	Life Test, 150C	300 hours	3/231/0
	ELFR	Early Life Failure Rate, 150C	24 hours	3/2400/0
	AC	Autoclave 121C	96 hours	3/231/0
	TC	Temperature Cycle, -65/150C	500 cycles	3/230/0
	THB	Biased Temperature and Humidity, 85C/85%RH	1000 hours	3/231/0
	HTSL	High Temperature Storage Life, 150C	1000 hours	1/77/0
	HBM	ESD – HBM	2500 V	1/3/0
	CDM	ESD – CDM	1000 V	1/3/0
	LU	Latch-up	25C	1/6/0
	ED	Electrical Characterization	Per Datasheet Parameters	Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:
Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com